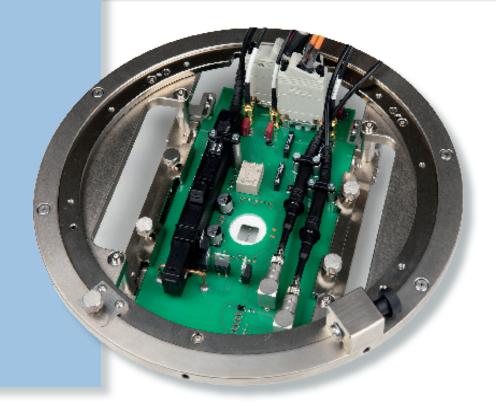


Ultra Fast Dynamic RDS_(ON) TEST

Characterization system for GaN-devices

FEATURES & BENEFITS

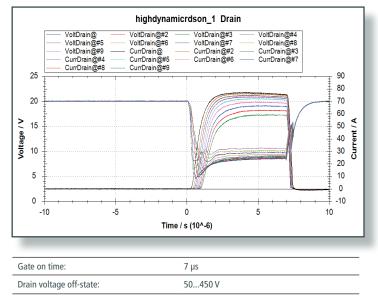
- Off-state 1 kV
- On-state 100 A
- 100 ns sampling time resolution
- Integrated wafer test solution for MPI TS2000-HP & TS3000-HP
- Active probe card
- Gate pulse length 1-100 µs
- Unipolar n-channel or p-channel
- Output characteristic
- Transfer characteristic

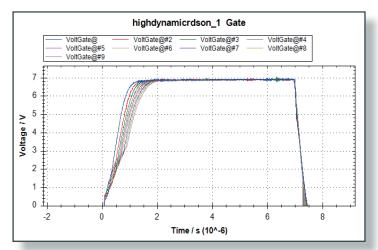


The Ultra Fast Dynamic RDS(on) test is designed for characterization of GaN transistors. A critical requirement in power electronics is obtaining a very low ON resistance (RON) immediately after switching from a high-voltage OFF state to a low-voltage ON state.

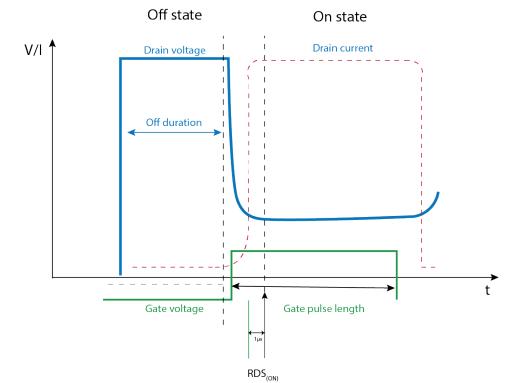
The Ultra Fast Dynamic RDS(on) test is able to measure the RDS(on) immediately after switching between OFF state and ON state. The first RDS(on) value is generated after approx. 1 µs. The system is designed for currents up to 100 A (pulsed) and voltages up to 1 kV. Due to the special design of the probecard it is possible to measure further parameters (leakage, and others).

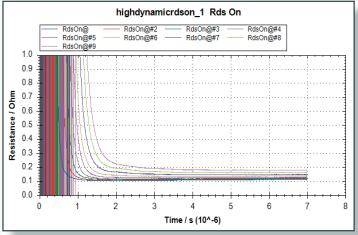
RDS(on) Switching Characteristics





• Shows the gate pulse shape depend on drain voltage off-state





• IDrain, VDrain for RDS (on)

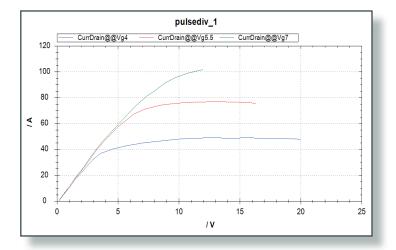
Off state parameters

Drain voltage: 01000 V	I _D leakage
Off duration	RDS(on) 100 μs x [n] @ 1 kV max.
On duration	1100 µs, 10100 A
Gate voltage @ Off \pm 10 V	RDS(on)

On state parameters

Gate pulse length: 1100 µs	Drain voltage: 80 mV resolution
Gate pulse voltage: 0 \pm 10 V	Drain current: 100 A max.
First RDS(on): 1 µs	RDS(on) settling 1 μs @ 100 A 500 ns @ 10 A

Output Characteristics



	up to 100 A pulsed @ 2 µs pulse width up to 10 A pulsed @ 1 µs pulse width
DC Pulse	
ID:	50 A (100 A) pulsed 400 µs
Vds:	± 40 V
DC	
ID:	20 A
Vds:	± 5 V

up to 100 A pulsed @ 2 us pulse width

System & Software Setup



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